

**Search Notes**

Application/Control No.

10/005,778

Examiner

Erin M. File

Applicant(s)/Patent under  
Reexamination

LI ET AL.

Art Unit

2634

**SEARCHED**

Class	Subclass	Date	Examiner
375	343	12/17/2004	EMF
714	796	12/17/2004	EMF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	316	12/17/2004	EMF
375	340	12/17/2004	EMF
375	343	12/17/2004	EMF

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM	12/17/2004	EMF
PALM INVENTORSHIP	12/17/2004	EMF
IEEE Explore Keyword Search	12/20/2004	EMF
IEEE Explore Article Search	12/20/2004	EMF